## 120-/128-OUTPUT TFT-LCD GATE DRIVER

The $\mu$ PD16650 is a TFT-LCD gate driver. Provided with a level shift circuit at the logic input, this chip can output a high gate scan voltage for a CMOS-level input. The $\mu$ PD16650 has an output change-over function for switching from the 120 -output mode to the 128 -output mode, and vice versa, thereby supporting the VGA, SVGA, and XGA panels. Its output enable function $(\overline{\mathrm{OE}})$ enables installing the driver on either side.

## FEATURES

- Output with high dielectric strength (on/off range: Vdd - Vee1 = 40 Vmax.)
- Built-in shift direction change-over function
- Shiftable negative supply voltage ( $\mathrm{V}_{\mathrm{EE} 1}$ ) level (shift range: $\left|\mathrm{VEE}_{\mathrm{EE}}-\mathrm{V}_{\mathrm{EE} 2}\right|=10 \mathrm{~V}$ )
- Two acceptable CMOS input levels (3.3 and 5 V )
- Output enable function
- MC-selectable output count (MC = high: 120-output mode)
(MC = low : 128-output mode)
- Slim TCP


## ORDERING INFORMATION

| Part number | Package |
| :---: | :---: |
| $\mu \mathrm{PD} 16650 \mathrm{~N}-\times \times \times$ | TCP (TAB package) |
| $\mu \mathrm{PD} 16650 \mathrm{~N}-\times \times \times$ | Standard TCP (OL pitch $=220 \mu \mathrm{~m})$ |

Remark When ordering, the customer can specify the external form of the TCP. Call one of our sales representatives for more information.

## BLOCK DIAGRAM



Remark LS (level shifter): Interfaces the 5 V CMOS level with the $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\text {EE2 }}$ level.

PIN CONNECTION DIAGRAM ( $\mu$ PD16650N- $\times \times \times$ )


Caution The Vcha pin should be connected to the Vdd or VEE2 pin on the TCP. (This method eliminates the necessity to provide the Vсна input pin on the TCP, resulting in a reduction in the number of required input pins.)

## PIN DESCRIPTION

| Pin symbol | Pin name | Description of function |
| :---: | :---: | :---: |
| $\mathrm{X}_{1}$ to $\mathrm{X}_{128}$ | Driver output | Output scan signals to drive the TFT-LCD gate electrodes. The output changes when the shift clock $\phi_{\mathrm{x}}$ rises. The amplitude of the driver output is $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE} 1}$. See the timing charts shown later for details of how to switch between the 120output mode and 128-output mode. |
| MC | Output count change-over input | Receives a signal that changes the number of outputs. For the 120-output mode, this pin must be supplied with a high level (Vcc). For the 128-output mode, it must be supplied with a low level (Vss or Veez). |
| V CHA | Logic voltage change-over input | Must be supplied with the $\mathrm{V}_{\text {EE2 }}$ level when the logic supply voltage is 3.3 V , and with the $V_{D D}$ level when the logic supply voltage is 5.0 V . |
| STVR STVL | Start pulse input/output | Receives an input to the internal shift register. The input data is loaded on the shift register at the positive-going edge of the shift clock $\phi_{\mathrm{x}}$. The scan signals are output from $\mathrm{X}_{1}$ to $\mathrm{X}_{128}$. The input/output level is the CMOS level. |
|  |  | Outputs a start pulse to the next stage if a cascade connection is used. In the 120-output mode, the start pulse is output at the negative-going edge of the 120 th shift clock $\phi_{x}$ pulse, and cleared at the negative-going edge of the 121 st pulse. In the 128-output mode, the start pulse is output at the negative-going edge of the 128 th shift clock $\phi_{x}$ pulse, and cleared at the negative-going edge of the 129th pulse. |
| R/L̄ | Shift direction change-over input | $\begin{aligned} & R / L=\text { high (for shift right): }: S T V R \rightarrow X_{1} \rightarrow X_{128} \rightarrow \text { STVL } \\ & R / L=\text { low (for shift left) }: S T V L \rightarrow X_{128} \rightarrow X_{1} \rightarrow \text { STVR } \end{aligned}$ |
| $\phi_{x}$ | Shift clock input | Receives a shift clock pulse for the internal shift register. A shift occurs at the positive-going edge of the shift clock pulse. |
| $\overline{\mathrm{OE}}$ | Output enable input | When this pin is at a high level, the driver output is fixed at a low level. The shift register is not cleared, however. The internal logic circuit operates even when the pin is at a high level. The signal supplied to this pin is not synchronized with the clock. |
| VDD | Driver positive supply voltage | Receives the supply voltage for both the logic circuit and driver. |
| V cc | Reference voltage | $5 \pm 0.5 \mathrm{~V} / 3.3 \pm 0.3 \mathrm{~V}$ <br> Reference voltage for the LS1 and LS2 level shifters. |
| Vss | Ground | Must be connected to the system ground. |
| VEE1 | Driver negative supply voltage | $\mathrm{V}_{\mathrm{EE} 1}$ (for the driver) |
| VEE2 | Driver negative supply voltage | $\mathrm{V}_{\text {eE2 }}$ (for the logic circuit) |

## CAUTIONS FOR USE

1) Power-on sequence

To prevent latch-up disruption, the power must be switched on in the order:
VCC $\rightarrow$ VEE1 $\rightarrow$ VEE2 $\rightarrow$ VDD $\rightarrow$ Logic input
When witching off, reverse the order. This order must be observed also during transition.
2) Insertion of bypass capacitors

The internal logic circuit operates at a high voltage. To make $\mathrm{V}_{\mathrm{IH}}$ and $\mathrm{V}_{\mathrm{IL}}$ immune to noise, use capacitors of $0.1 \mu \mathrm{~F}$ or so between supply voltages as shown below.

3) Negative voltage level shift

If it is necessary to shift the level of a negative supply voltage, shift the $\mathrm{V}_{\mathrm{EE} 1}$ (driver supply voltage) level. The shift should be limited to within: $\mathrm{V}_{\text {EE } 2} \leq \mathrm{V}_{\text {EE }} \leq \mathrm{V}_{\mathrm{EE} 2}+10 \mathrm{~V}$
Note that shifting the $\mathrm{V}_{\mathrm{EE} 1}$ level results in the ON-state output resistance and output fall time ratings being changed.
4) Handling the VEE1 and VEE2 driver negative supply voltage pins

For applications in which a negative supply voltage level is not shifted, connect the VEE1 pin (driver supply voltage) to the Veez pin (logic supply voltage) outside the TCP. Fix all unused input pins to the Veez level.

TIMING CHART (MC = Vss, 128-OUTPUT MODE, AND R/L=Vcc)


Caution Do not change all outputs simultaneously, because such a sequence may result in malfunction.

TIMING CHART (MC = Vcc, 120-OUTPUT MODE, AND R/ $\bar{L}=\mathrm{Vcc}$ )


Cautions 1. Do not change all outputs simultaneously, because such a sequence may result in malfunction.
2. The output sequence in the 120 -output mode is as follows: STVR (STVL) $\rightarrow \mathbf{X}_{1} \rightarrow \mathbf{X}_{2} \ldots \mathbf{X}_{60} \rightarrow \mathbf{X}_{69} \ldots \mathbf{X}_{127} \rightarrow \mathbf{X}_{128} \rightarrow$ STVL (STVR)

ABSOLUTE MAXIMUM RATINGS ( $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, Vss $=0 \mathrm{~V}$ )

| Parameter | Symbol | Conditions | Rated value | Unit |
| :---: | :---: | :---: | :---: | :---: |
| Supply voltage | VdD |  | -0.5 to +28 | V |
| Supply voltage | Vcc |  | -0.5 to +7 | V |
| Supply voltage | $\begin{aligned} & V_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE} 1} \\ & \mathrm{~V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE} 2} \end{aligned}$ |  | -0.5 to +42 | V |
| Supply voltage | $\mathrm{V}_{\text {EE1, }} \mathrm{V}_{\text {EE2 }}$ |  | -22 to +0.5 | V |
| Input voltage | VI |  | $\mathrm{V}_{\text {EE2 } 2}-0.5$ to $\mathrm{V}_{\text {do2 }}+0.5$ | V |
| Input current | 1 |  | $\pm 10$ | mA |
| Output current | Io |  | $\pm 10$ | mA |
| Operating temperature range | $\mathrm{T}_{\mathrm{A}}$ |  | -20 to +85 | ${ }^{\circ} \mathrm{C}$ |
| Storage temperature range | $\mathrm{T}_{\text {stg }}$. |  | -55 to +125 | ${ }^{\circ} \mathrm{C}$ |

RECOMMENDED OPERATING RANGES ( $\mathrm{T}_{\mathrm{A}}=\mathbf{- 2 0}{ }^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$, Vss $=\mathbf{0}$ V)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply voltage | VDD |  | 16 |  | 25 | V |
| Supply voltage | VEE1 |  | $\mathrm{V}_{\text {EE } 2}$ |  | $\mathrm{V}_{\text {EE } 2}+10$ | V |
| Supply voltage | $V_{\text {EE2 }}$ |  | -20 |  | 0 | V |
| Supply voltage | $\begin{aligned} & V_{D D}-V_{\text {EE1 }} \\ & V_{D D}-V_{\text {EE2 }} \end{aligned}$ |  | 20 |  | 40 | V |
| Supply voltage | Vcc | For the 3.3 V logic input | 3.0 | 3.3 | 3.6 | V |
| Supply voltage | V cc | For the 5.0 V logic input | 4.5 | 5.0 | 5.5 | V |

Remark When shifting the level of $\mathrm{V}_{\mathrm{EE} 1}$ (driver supply voltage), satisfy the condition:
$\mathrm{V}_{\text {EE } 2} \leq \mathrm{V}_{\text {EE }} \leq \mathrm{V}_{\text {EE }}+10 \mathrm{~V}$
Note that shifting the $\mathrm{V}_{\mathrm{EE} 1}$ level results in the ON-state output resistance and output fall time ratings being changed.

## ELECTRICAL CHARACTERISTICS

$\left(\mathrm{T}_{\mathrm{A}}=-20{ }^{\circ} \mathrm{C}\right.$ to $+70^{\circ} \mathrm{C}, \mathrm{Vdd}=20 \mathrm{~V}, \mathrm{VEE}_{\mathrm{V}}=\mathrm{VEE} 2=-20 \mathrm{~V}, \mathrm{Vcc}=3.3 \pm 0.3 \mathrm{~V}$ or $5.0 \pm 0.5 \mathrm{~V}$, $\left.\mathrm{Vss}=0 \mathrm{~V}\right)$

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Input high voltage | $\mathrm{V}_{\mathrm{H}}$ | Other than $\mathrm{V}_{\text {сна }}$ | 0.7 V cc |  | Vcc | V |
| Input low voltage | VIL | Other than $\mathrm{V}_{\text {cha }}$ | $\mathrm{V}_{\text {EE2 }}$ |  | 0.3Vcc | V |
| Output high voltage | Vон | STVR(STVL), $\mathrm{loh}=-40 \mu \mathrm{~A}$ | V cc - 0.4 |  | V co | V |
| Output low voltage | Vol | STVR(STVL), lol $=40 \mu \mathrm{~A}$ | Vss |  | Vss +0.4 | V |
| Output high current | Іхон | $\mathrm{X}_{\mathrm{n}}, \mathrm{V}_{\mathrm{x}}=\mathrm{V}_{\mathrm{DD}}-1 \mathrm{~V}$ |  |  | -1.5 | mA |
| Output low current | Ixol | $\mathrm{X}_{\mathrm{n}}, \mathrm{V}_{\mathrm{x}}=\mathrm{V}_{\text {EE } 1}+1 \mathrm{~V}$ | 1.5 |  |  | mA |
| ON-state output resistance | Ron1 | $\mathrm{V}_{\mathrm{X}}=\mathrm{V}_{\text {EE } 1}+1 \mathrm{~V}$ or $\mathrm{V}_{\mathrm{DD}}-1 \mathrm{~V}$ |  |  | 660 | $\Omega$ |
| Input leakage current | IIL | $\mathrm{V}_{1}=0 \mathrm{~V}, 5.0 \mathrm{~V}$, or 3.3 V |  |  | $\pm 1.0$ | $\mu \mathrm{A}$ |
| Dynamic drain current | Ido | $\mathrm{V}_{\mathrm{DD}}, \mathrm{f} \phi_{\mathrm{x}}=31.5 \mathrm{kHz}$ |  | 0.5 | 1.0 | mA |
|  | IEE | $\mathrm{V}_{\text {EE1 } 12, ~} \mathrm{f} \phi_{\mathrm{x}}=31.5 \mathrm{kHz}$ |  | -0.5 | -1.0 | mA |
|  | Icc | $\mathrm{Vcc}, \mathrm{f} \phi_{\mathrm{x}}=31.5 \mathrm{kHz}$ |  | 50 | 100 | $\mu \mathrm{A}$ |

## SWITCHING CHARACTERISTICS

$\left(\mathrm{T}_{\mathrm{A}}=-20^{\circ} \mathrm{C}\right.$ to $+70^{\circ} \mathrm{C}, \mathrm{Vdd}=20 \mathrm{~V}, \mathrm{VeE}_{\mathrm{D}}=\mathrm{VEE} 2=-20 \mathrm{~V}, \mathrm{Vss}=0 \mathrm{~V}, \mathrm{Vcc}=3.3 \pm 0.3 \mathrm{~V}$ or $\left.5.0 \pm 0.5 \mathrm{~V}\right)$

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| STVR and STVL output delay | tPHL1 | $\begin{aligned} & \mathrm{CL}=20 \mathrm{pF} \\ & \mathrm{CLK} \rightarrow \mathrm{STVR}(\mathrm{STVL}) \end{aligned}$ |  |  | 600 | ns |
|  | tpLH1 |  |  |  | 600 | ns |
| Driver output delay | tpHL2 | $\begin{aligned} & \mathrm{CL}=220 \mathrm{pF} \\ & \mathrm{CLK} \rightarrow \mathrm{X}_{\mathrm{n}} \end{aligned}$ |  |  | 700 | ns |
|  | tpLH2 |  |  |  | 700 | ns |
|  | td1 | $\mathrm{CL}=220 \mathrm{pF}, \overline{\mathrm{OE}}: \mathrm{L} \rightarrow \mathrm{H}$ |  |  | 700 | ns |
|  | td2 | $\mathrm{CL}=220 \mathrm{pF}, \overline{\mathrm{OE}}: \mathrm{H} \rightarrow \mathrm{L}$ |  |  | 700 | ns |
| Output rise time | tтhL | $\mathrm{CL}=220 \mathrm{pF}$ |  |  | 300 | ns |
| Output fall time | ttLH | $\mathrm{CL}=220 \mathrm{pF}$ |  |  | 300 | ns |
| Input capacitance | $\mathrm{Cl}_{1}$ | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | 15 | pF |
| Maximum clock frequency | ${ }^{\dagger} \phi_{x}$ | For cascade connection | 100 |  |  | kHz |

## TIMING REQUIREMENTS

$\left(\mathrm{TA}_{\mathrm{A}}=-20^{\circ} \mathrm{C}\right.$ to $+70^{\circ} \mathrm{C}, \mathrm{Vdd}=20 \mathrm{~V}, \mathrm{VeE}_{\mathrm{V}}=\mathrm{VEE} 2=-20 \mathrm{~V}, \mathrm{Vss}=0 \mathrm{~V}, \mathrm{Vcc}=3.3 \pm 0.3 \mathrm{~V}$ or $\left.5.0 \pm 0.5 \mathrm{~V}\right)$

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
| :--- | :--- | :--- | :--- | :--- | :--- | :---: |
| Clock pulse high width | PW $\phi_{x}(\mathrm{H})$ | Duty $=50 \%$ | 500 |  |  | ns |
| Clock pulse low width | PWW $\phi_{x}(\mathrm{~L})$ | Duty $=50 \%$ | 500 |  |  | ns |
| Data setup time | tsetup | STVR(STVL) $\uparrow \rightarrow$ CLK $\uparrow$ | 100 |  |  | ns |
| Data hold time | thold | CLK $\uparrow \rightarrow$ STVR(STVL) $\downarrow$ | 100 |  |  | ns |

Remark The logic input rise time ( tr ) and fall time ( $\mathrm{t}_{\mathrm{f}}$ ) must be within 20 ns (between $10 \%$ and $90 \%$ of the peak amplitude of the input).

SWITCHING CHARACTERISTIC WAVEFORM (R/L = HIGH)


## RECOMMENDED MOUNTING CONDITIONS

When mounting this product, please make sure that the following recommended conditions are satisfied.
For packaging methods and conditions other than those recommended below, please contact NEC sales personnel.
$\mu$ PD16650N- $\times \times \times$

| Mounting Condition | Mounting Method | Condition |
| :--- | :--- | :--- |
| Thermocompression | Soldering | Heating tool 300 to $350{ }^{\circ} \mathrm{C}$; heating for 2 to 3 seconds; pressure 100 g <br> (per solder) |
|  | ACF (Sheet-shape bonding <br> agent) | Temporary bonding 70 to $100{ }^{\circ} \mathrm{C}$; pressure 3 to $8 \mathrm{~kg} / \mathrm{cm}^{2}$; time 3 to 5 <br> secs. <br> Real bonding 165 to $180{ }^{\circ} \mathrm{C}$; pressure 25 to $45 \mathrm{~kg} / \mathrm{cm}^{2}$; time 30 to 40 <br> secs. (when using the anisotropic conductive film SUMIZAC1003 of <br> Sumitomo Bakelite, Ltd.) |

Caution To find out the detailed conditions for packaging the ACF part, please contact the ACF manufacturing company. Be sure to avoid using two or more packaging methods at a time.

## Reference

NEC Semiconductor Device Reliability/Quality Control System (IEI-1212)
Quality Grades to NEC's Semiconductor Devices (IEI-1209)

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